

**Achieving Color-tunable Luminescence in CaF₂: Eu Phosphor for Multimode
Anti-counterfeiting**

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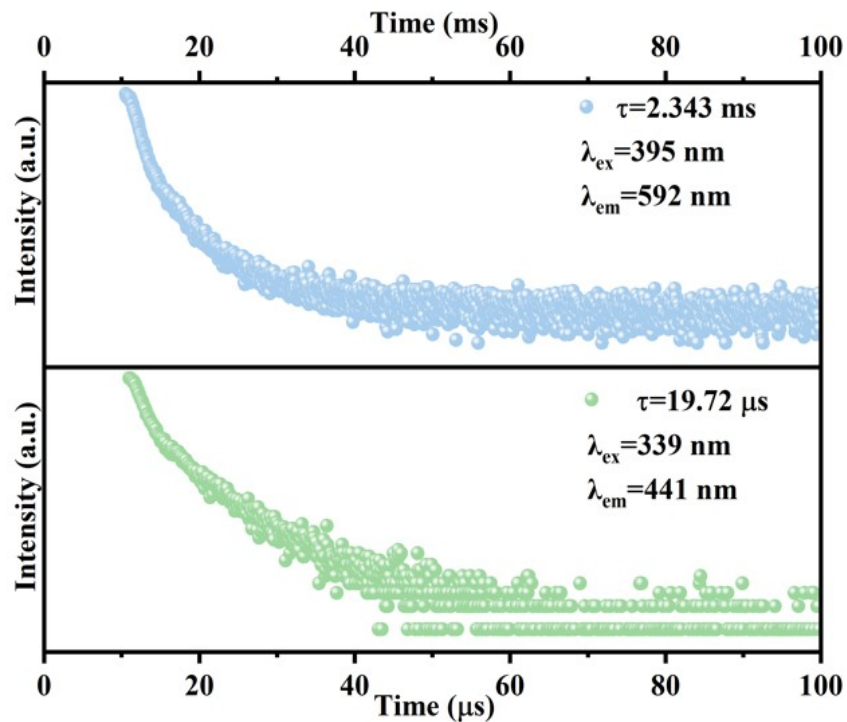


Fig. S1. Time luminescence decay curves of $\text{CaF}_2: 0.5\% \text{Eu}$ under the emissions at 592 and 441 nm, respectively.

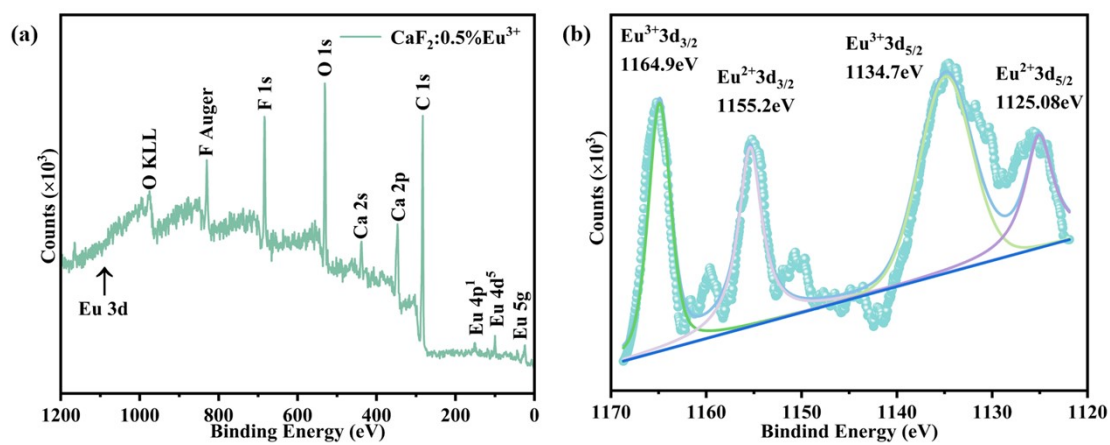


Fig. S2. XPS spectra of $\text{CaF}_2: 0.5\% \text{Eu}$: (a) survey, (b) high-resolution scans of Eu 3d.

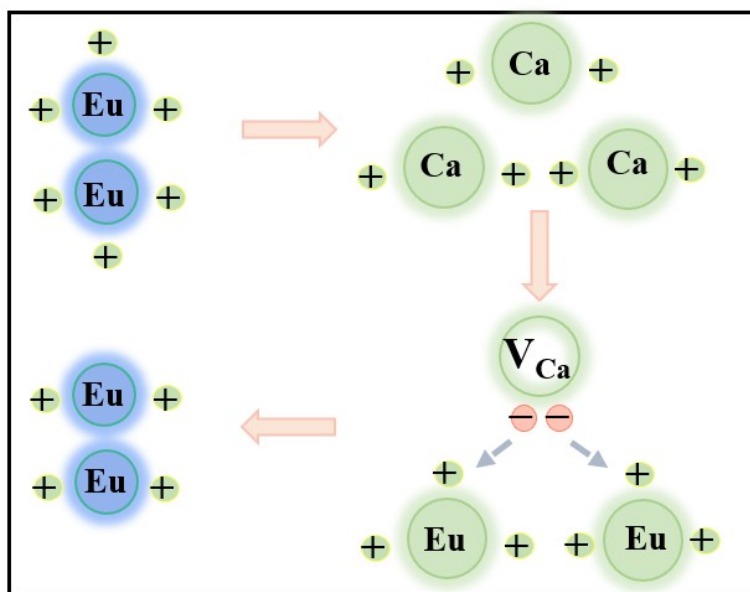


Fig. S3. The schematic diagram of the Eu^{3+} self-reduction principle.

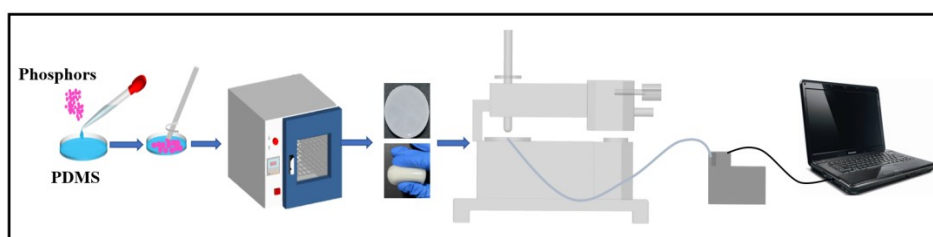


Fig. S4. Schematic diagram depicting the ML measurement for the $\text{CaF}_2: x\% \text{Eu}^{3+} @ \text{PDMS}$ ($x = 0.1, 0.25, 0.5\%, 0.75,$ and 1) film.

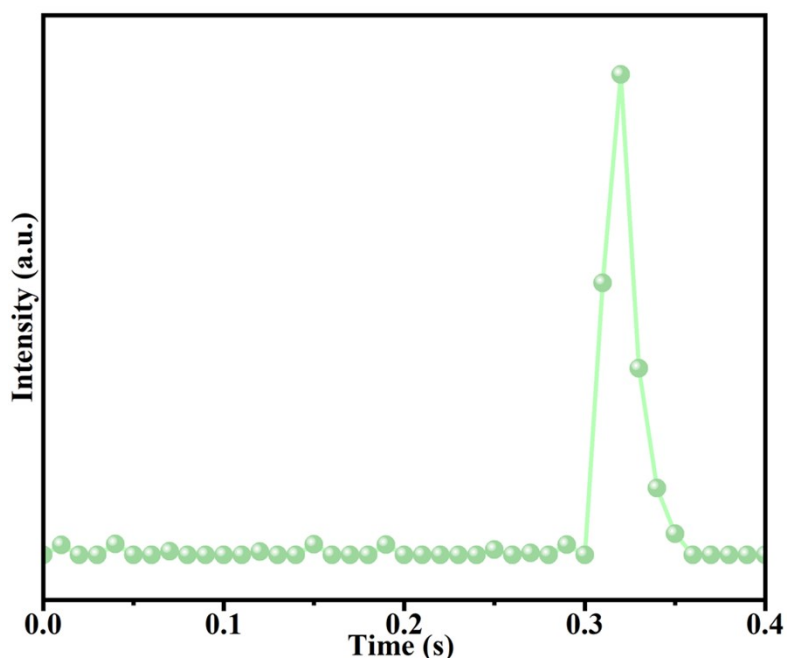


Fig. S5. The response speed of $\text{CaF}_2: 0.5\% \text{Eu} @ \text{PDMS}$ to mechanical stimuli.

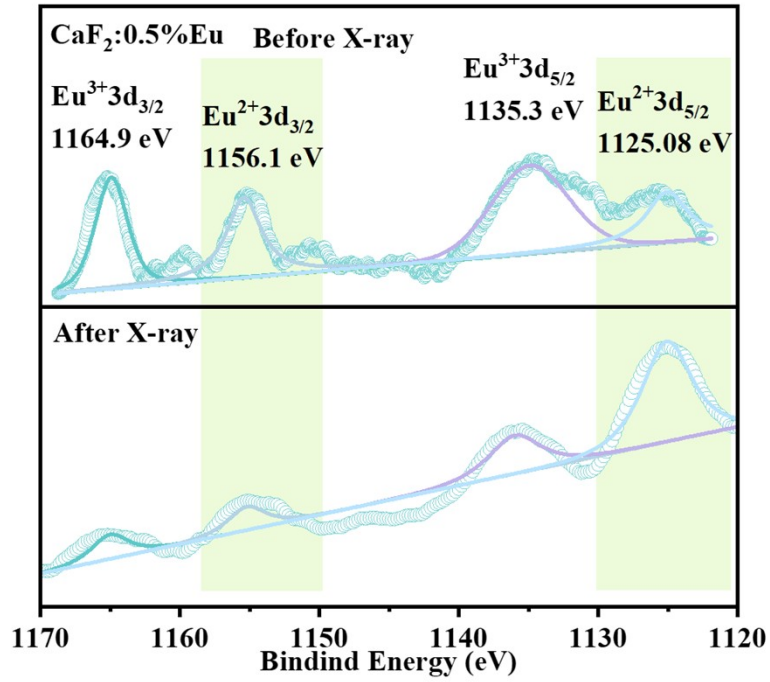


Fig. S6. XPS spectra of $\text{CaF}_2:0.5\%\text{Eu}$ before and after x-ray irradiation.

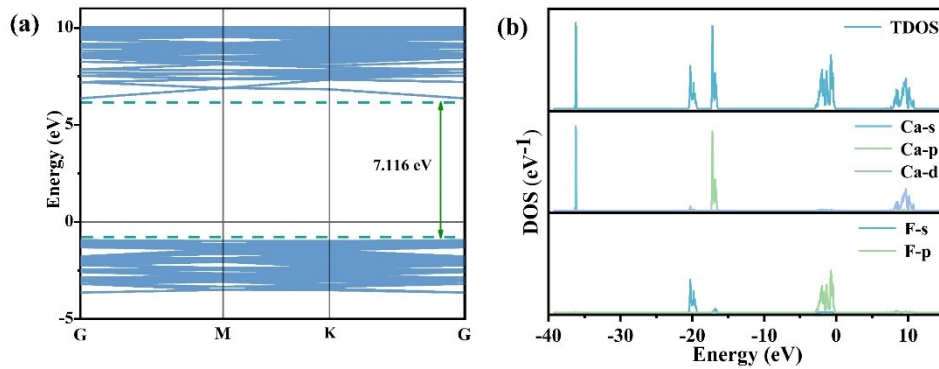


Fig. S7. (a) The band structure, (b) the total DOS and partial DOS of the CaF_2 host.

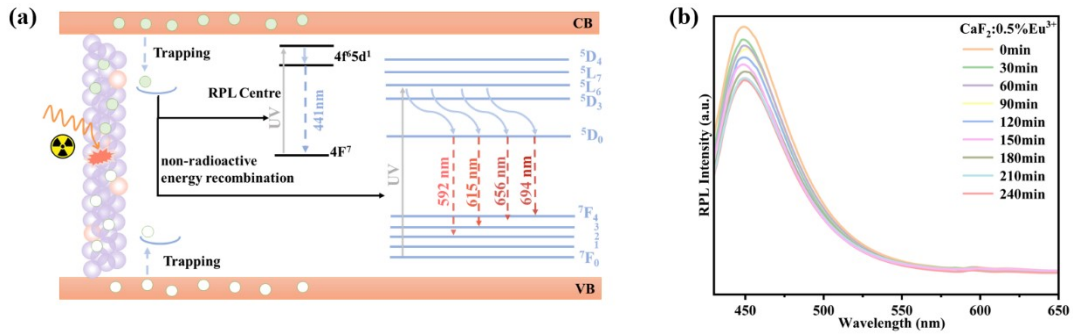


Fig. S8. (a) The mechanism of RPL phenomenon. (b) Standing for different times after X-ray irradiation.